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NIST's Polarized Resonant Soft X-ray Scattering facility to measure chemical structure and molecular orientation on the nano-scale

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— NIST is developing a new Polarized Resonant Soft X-ray Scattering (P-RSoXS) facility at the NSLS-II synchrotron located in Brookhaven National Laboratory. This facility will enable the highest quality ensemble measurements of the nanoscale distribution of molecular species and orientations in both high-throughput ex-situ measurements and diverse specialized in-situ experiments. The facility's current state of design will be presented, along with a survey of applications in fields from thin-film organic electronics, and biology to energy and environmental sciences. A dialog with the community regarding potential applications is encouraged.

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